YZ-WG3N30N

FEATURES

High Luminous Output White LED Lamp

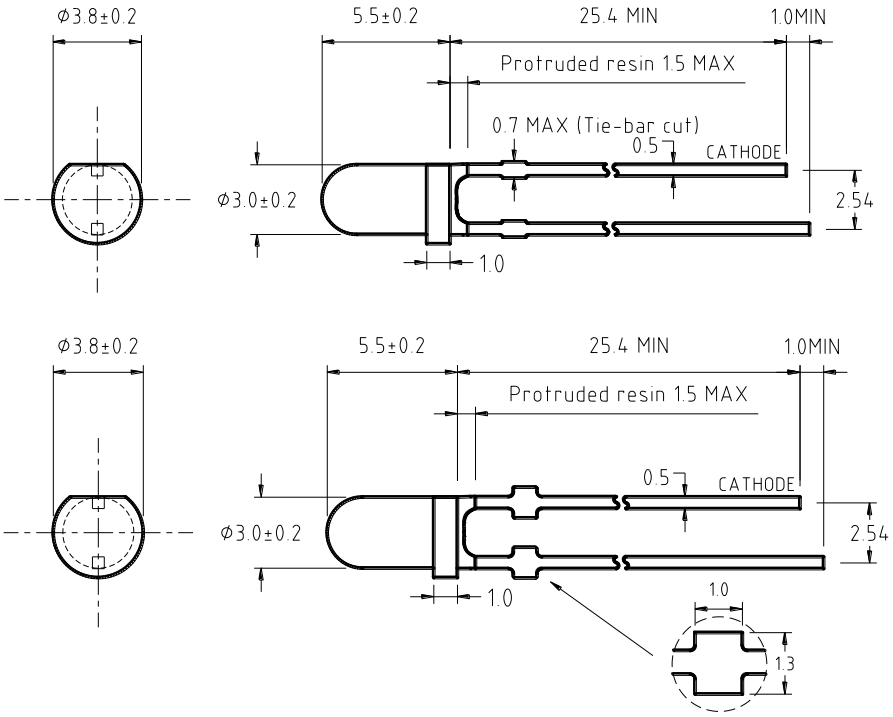
Chip Technology ─ InGaN

Golden Tinted Epoxy Package

Lens Size 3mm with 5mm option

Viewing Angles 2θ ½ = 30°

Package Dimensions



Notes:

1. All dimensions are in millimeters (inches).
2. Tolerance ± 0.25 (0.01”) mm unless otherwise noted.
3. Protruded resin under flange is 1.0mm (0.04”) max.
4. Lead spacing is measured where the leads emerge from the package
5. Specifications are subject to change without notice.

Delivery

- **Bulk, 500 pieces per bag standard**
- **Ammo or Reel available upon request**

YZ-WG3N30N

Absolute Maximum Ratings at Ta = 25°C

Item	Symbol	Absolute Maximum Rating	Unit
DC Forward Current	I_F	20	mA
Peak Pulsed Forward Current ※	I_{FP}	150	mA
Reverse Voltage	V_R	5	V
Derating Factor		0.40	mA/ °C
Power Dissipation	Pd	120	mW
Operating Temperature	T_{opr}	-30 ~ +85 ℃	°C
Storage Temperature	T_{stg}	-40 ~ +100 ℃	°C
Solder Dipping Temperature	T_{sld}	260℃ for 5 sec	

Remarks: Duty Ratio = 1/16, Pulse Width = 0.1ms

Electrical / Optical Characteristics at Ta = 25°C

Parameter	Symbol	Min	Typ	Max	Unit	Test Condition
Forward Voltage	V_f	2.9	3.2	3.5	V	I_f = 20 mA
Luminous Intensity	I_v	2150		4500	mcd	I_f = 20 mA
Reverse Current	I_r			10	mA	V_R = 5V

Iv Ranks / Luminous Intensity Bin Limits @20mA

Bin Name	Min	Max
T	2100	4500

I_V Ranks Tolerance of each minimum and maximum is ± 15%

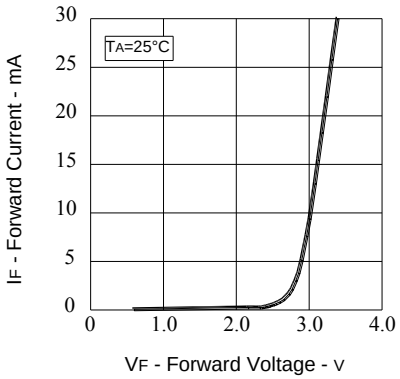
Color Ranks @20mA

CIE	X	0.480	0.483	0.483	0.486
	Y	0.433	0.438	0.429	0.434

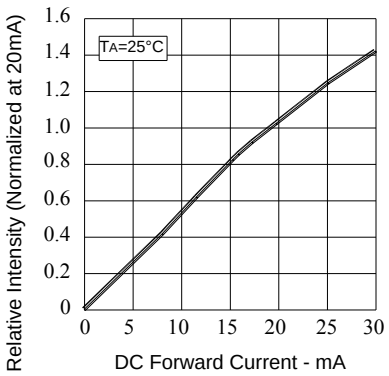
YZ-WG3N30N

Electrical / Optical Characteristics Diagram at Ta = 25°C

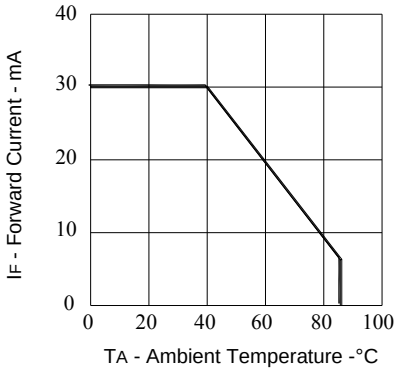
Forward Current vs.Forward Voltage

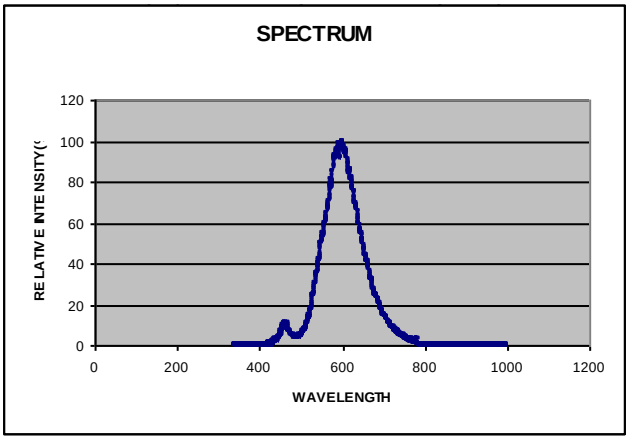


Relative Intensity vs.Forward Current



Forward Current vs.Ambient Temperature





Notes:

1. One delivery will include up to three-color ranks and two luminous intensity ranks of the products. The quantity-ratio of the ranks is decided by Yoldal.
2. All data showing in this product specification are measured by proper experiment conditions and instruments. However, those data may be different due to variations of testing instruments and conditions.

Electrostatic Sensitive Devices